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Journal articles indexed in SCI, SSCI, and AHCI

- I. **DGridSim: a multi-model discrete-event simulator for real-time data grid systems**
DOĞAN A., Atanak M. M., Tandogan S., ALTUĞ R. O., ŞENEL H. G.
SIMULATION-TRANSACTIONS OF THE SOCIETY FOR MODELING AND SIMULATION INTERNATIONAL, vol.90, no.11, pp.1209-1230, 2014 (SCI-Expanded)
- II. **Gradient Estimation Using Wide Support Operators**
Senel H. G.
IEEE TRANSACTIONS ON IMAGE PROCESSING, vol.18, no.4, pp.867-878, 2009 (SCI-Expanded)

Papers Presented at Peer-Reviewed Scientific Conferences

- I. **Gray Level Topological Angle Detection of High Curvature Points**
Cihan I. K., ŞENEL H. G.
IEEE International Symposium on Industrial Electronics (ISIE), Bari, Italy, 4 - 07 July 2010, pp.1618-1622, (Full Text)
- II. **Image Gradient Estimation with Wide Support Kernels**
ŞENEL H. G.
4th International Conference on Information and Automation for Sustainability, Colombo, Brazil, 12 - 14 December 2008, pp.270-272, (Full Text)
- III. **Turkish question answering - Question answering for distance education students**
Yurekli B., Arslan A., ŞENEL H. G., YILMAZEL Ö.
3rd International Conference on Software and Data Technologies, Oporto, Portugal, 5 - 08 July 2008, pp.320-321, (Full Text)
- IV. **Topolojiye Dayali Kose Tespiti Topology Based Corner Detection**
ŞENEL H. G., Cihan I. K.
IEEE 15th Signal Processing and Communications Applications Conference, Eskişehir, Turkey, 11 - 13 June 2007, pp.1103-1105, (Full Text)
- V. **Gray level topological corner detection**
Cihan I. K., ŞENEL H. G.
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- VI. **An application of topological median filters on detection and clustering of microcalcifications in digital mammograms**
Cihan I. K., ŞENEL H. G.
2006 IEEE International Conference on Acoustics, Speech and Signal Processing, ICASSP 2006, Toulouse, France, 14 - 19 May 2006, vol.2, (Full Text)